



# **Extreme-Precision MEMS Segmented Deformable Mirror (NASA Phase II SBIR )**

**Michael A. Helmbrecht, Ph.D.  
Iris AO, Inc.**

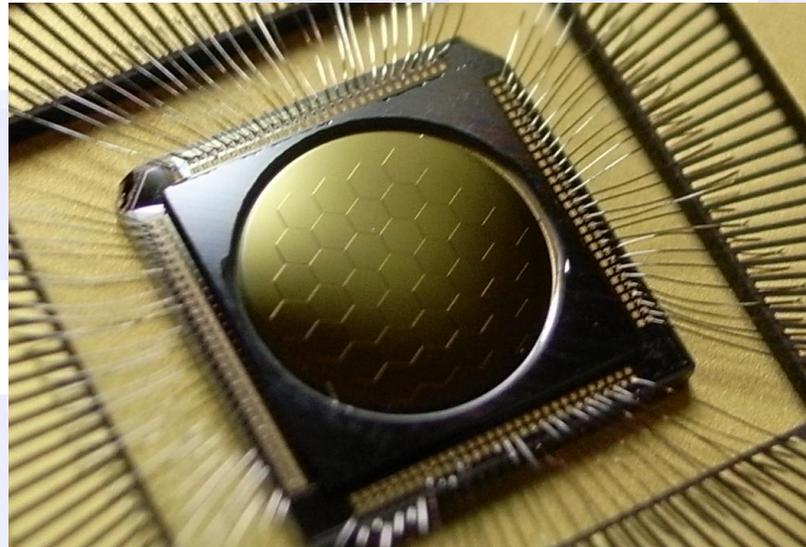
**[www.irisao.com](http://www.irisao.com)  
[michael.helmbrecht@irisao.com](mailto:michael.helmbrecht@irisao.com)  
[info@irisao.com](mailto:info@irisao.com)**

**Mirror Technology Days**

**August 25<sup>th</sup> – 27<sup>th</sup>, 2008**

# Precision DMs & Electronics

**Compact**



**Robust**

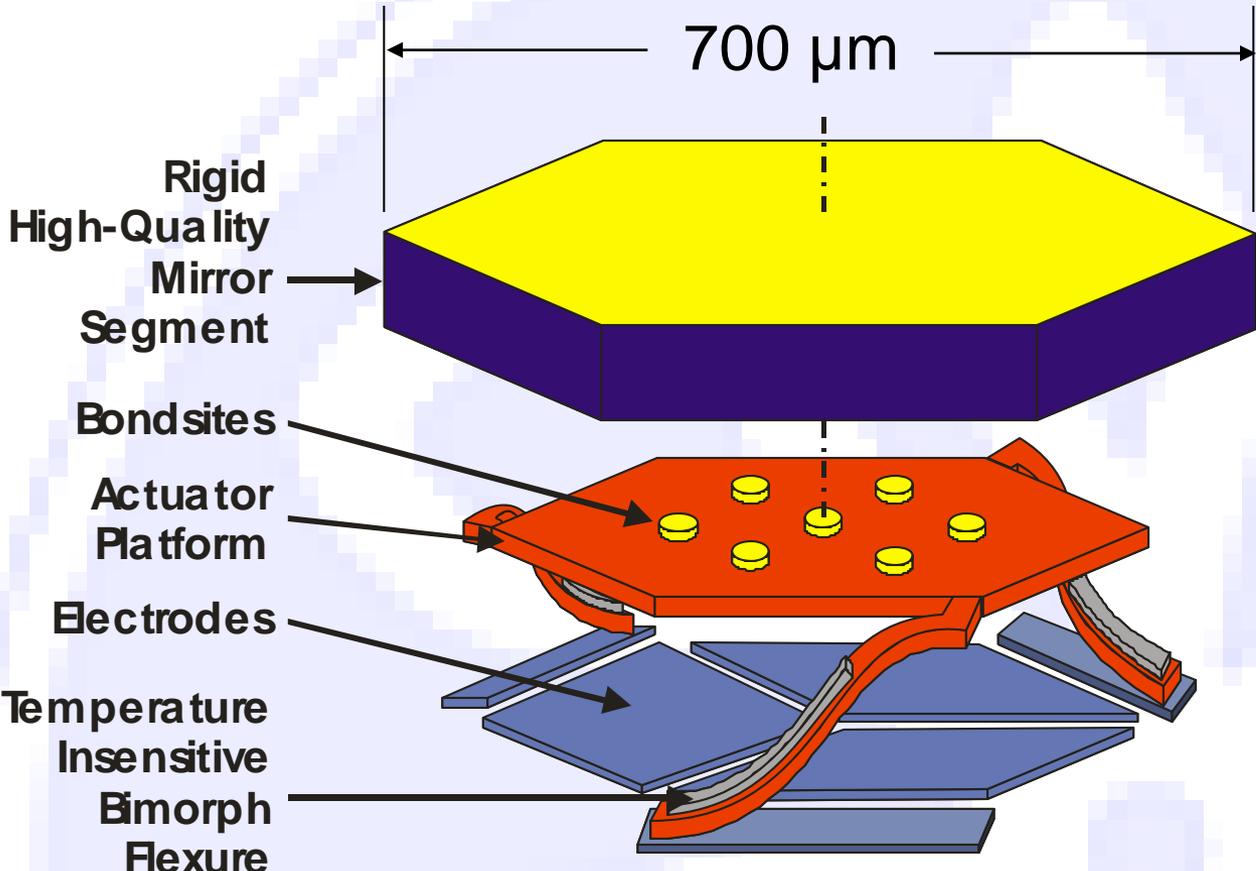
**Easy to Use**

# Outline

- Iris AO DM Segment
- NASA Phase II SBIR Progress
  - Precision MEMS DM
  - Precision drive electronics
- DM Scaling
  - NIH Phase II SBIR Progress
    - 163 segment DM
  - $10^3$  segment scaling demonstration



# Segmented MEMS DM Schematic



- Robust single-crystal-silicon assembled mirror surface stays flat ( $0.56 \text{ nm}/^\circ\text{C PV}$ )
- Temperature-insensitive bimorphs elevate mirror above substrate ( $14 \text{ nm}/^\circ\text{C}$ ,  $\sigma=0.8 \text{ nm}/^\circ\text{C}$ )
- Piston/tip/tilt electrostatic actuation
- 2.3 kHz frequency response
  - 170/200 μs rise/fall times, 10-90%

# Phase II SBIR Goals

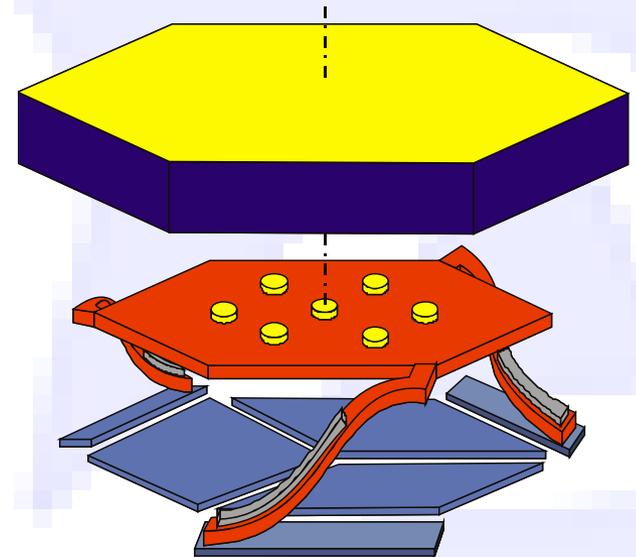
Performance Period: Jan 29 2007 – Jan 28, 2009

Specification	Start of Phase II	Phase II Demo Goal*	Phase II Study Goal	Today (8/2008)
Surface Figure Errors (nm <i>rms</i> )	6-20	1-3	0.1	5-11
Open-loop positioning accuracy ( <i>rms</i> )	20-30 nm	10 nm	Not Specified	8 nm (flattened)
Positioning resolution (nm <i>rms</i> )	5 (elect noise limited)	0.14	0.04	0.45 (0.11 PWM)
Stability (nm <i>rms</i> ) • over 15-60 min	0.2-1.2 (5 elect. noise)	0.2	0.04	TBD
<b>Failure Testing: Continue testing and determine techniques to eliminate potential snap-in failures</b>				

\* Independent verification by the Lab for AO at UC Santa Cruz

# Surface Figure Errors

- Current designs: 5-11 nm *rms*
  - Single-crystal-silicon segments
  - Segment thickness = 25  $\mu\text{m}$
- Thicker  Flatter
  - Surface figure errors   $1/t^{2-3}$
  - DMs with 50  $\mu\text{m}$ -thick mirrors will be fabricated by end of contract
    - Expect 4-8X improvement in *rms* figure errors



# Closed-Loop Flattened DM



Mag: 1.4 X  
Mode: PSI

## Surface Data

Date: 06/20/2008  
Time: 16:19:29

### Surface Statistics:

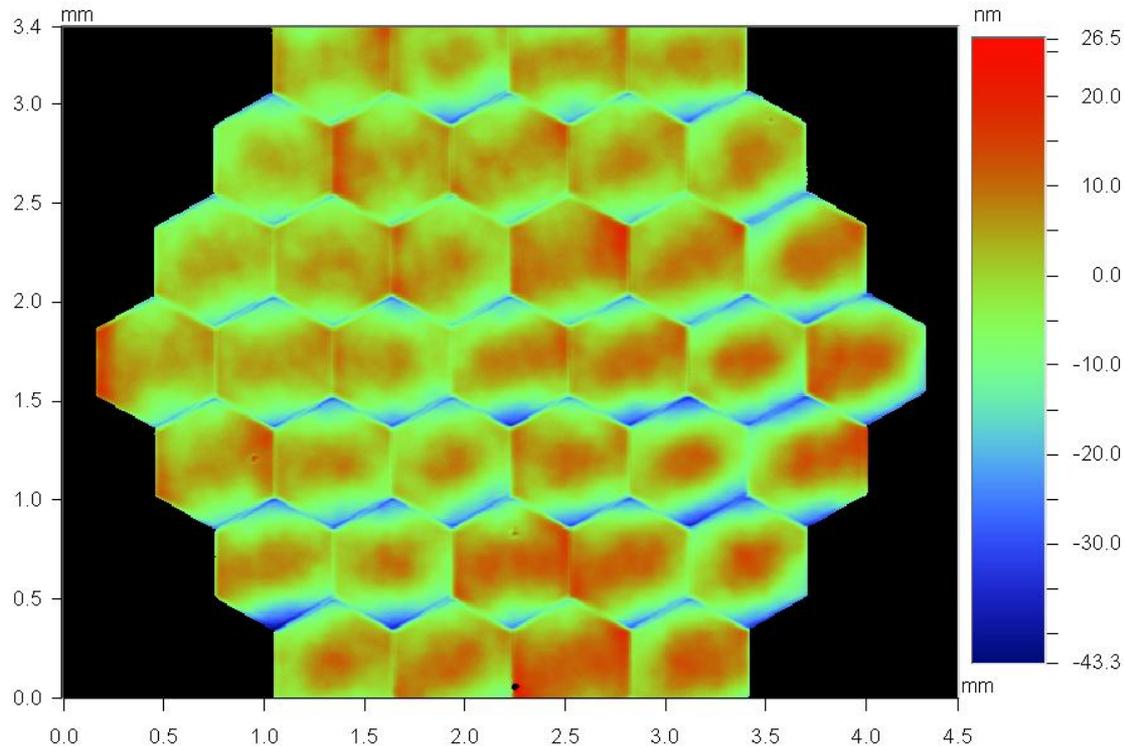
Ra: 6.04 nm  
Rq: 7.74 nm  
Rz: 55.73 nm  
Rt: 69.79 nm

### Set-up Parameters:

Size: 736 X 480  
Sampling: 6.06  $\mu$ m

### Processed Options:

Terms Removed:  
Tilt  
Filtering:  
None



Title: FSC37-01-07-0614

Note: Closed-Loop Flattened

August 26<sup>th</sup>, 2008

# Open-Loop Flattened DM



Mag: 1.4 X  
Mode: PSI

## Surface Data

Date: 06/19/2008  
Time: 16:02:01

### Surface Statistics:

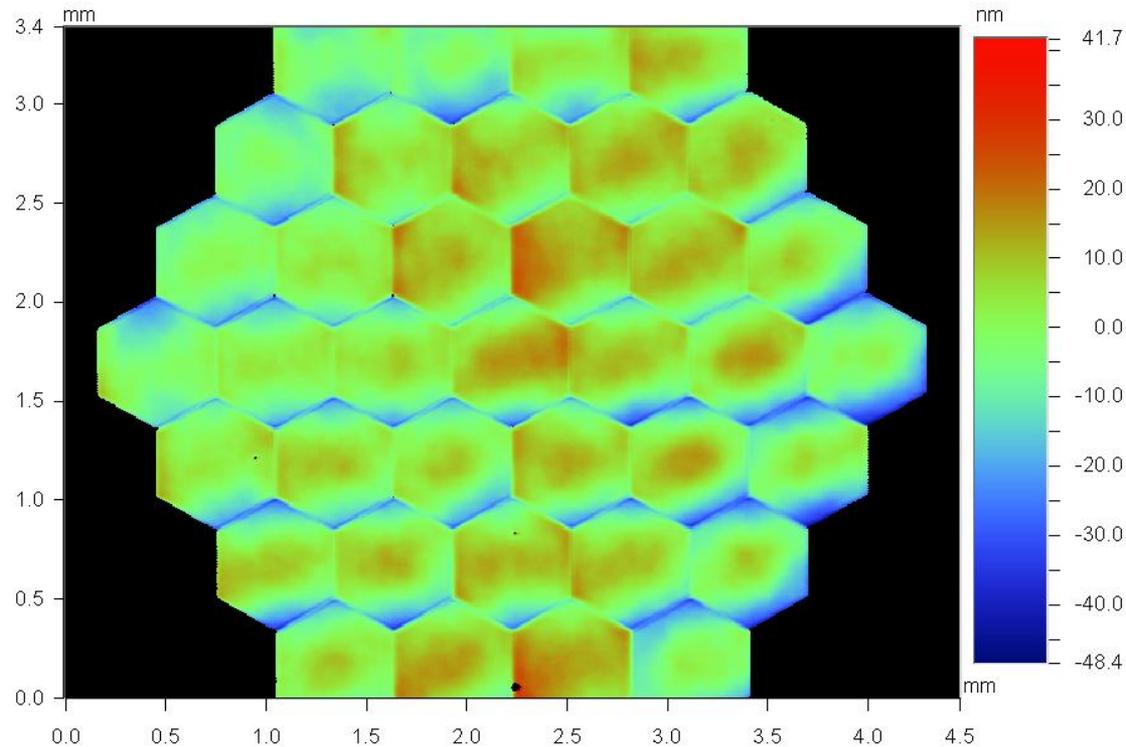
Ra: 7.28 nm  
Rq: 9.21 nm  
Rz: 67.65 nm  
Rt: 90.05 nm

### Set-up Parameters:

Size: 736 X 480  
Sampling: 6.06  $\mu$ m

### Processed Options:

Terms Removed:  
Tilt  
Filtering:  
None

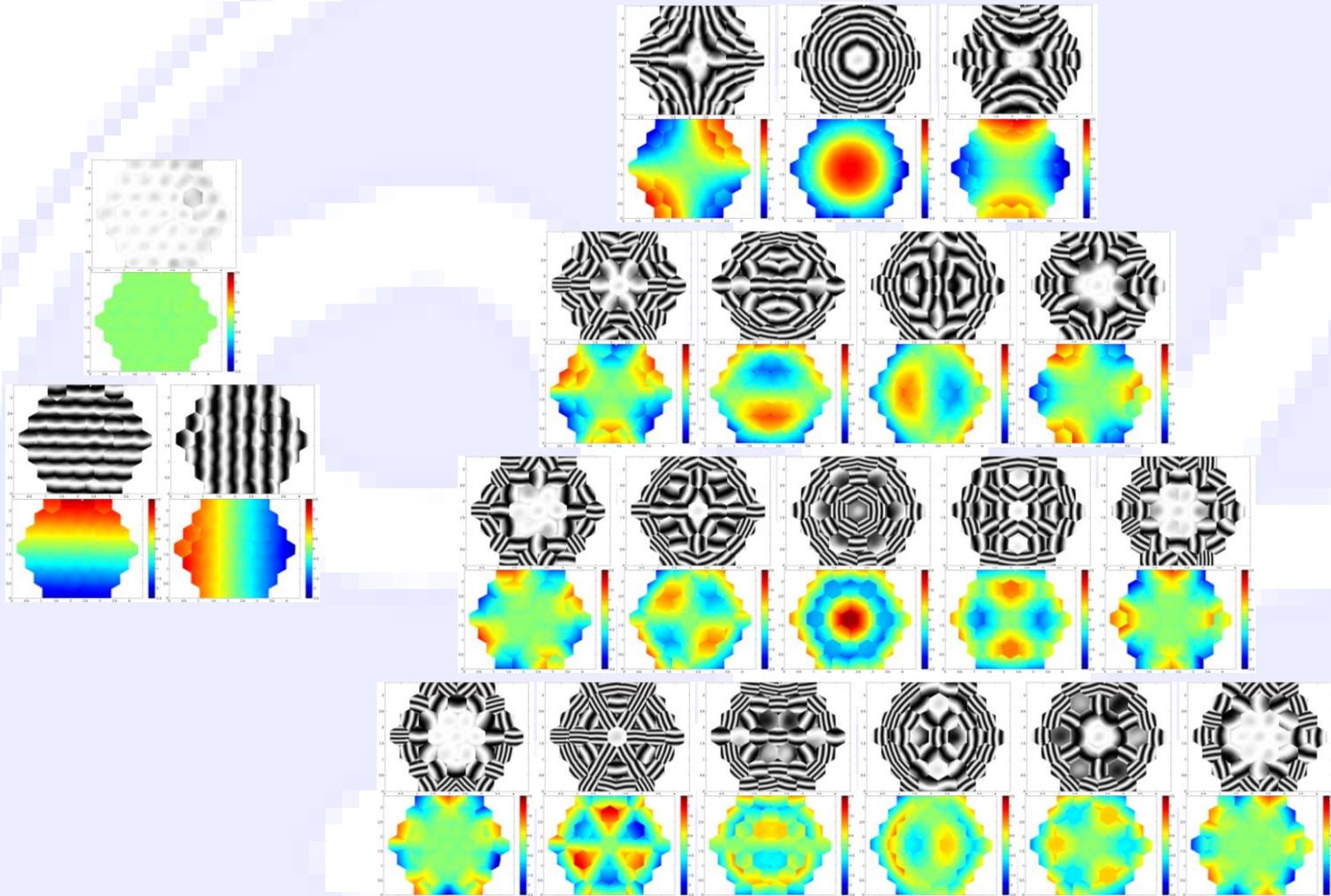


Title: FSC37-01-07-0614

Note: Open-Loop Flattened

August 26<sup>th</sup>, 2008

# Open-Loop Positioning Example

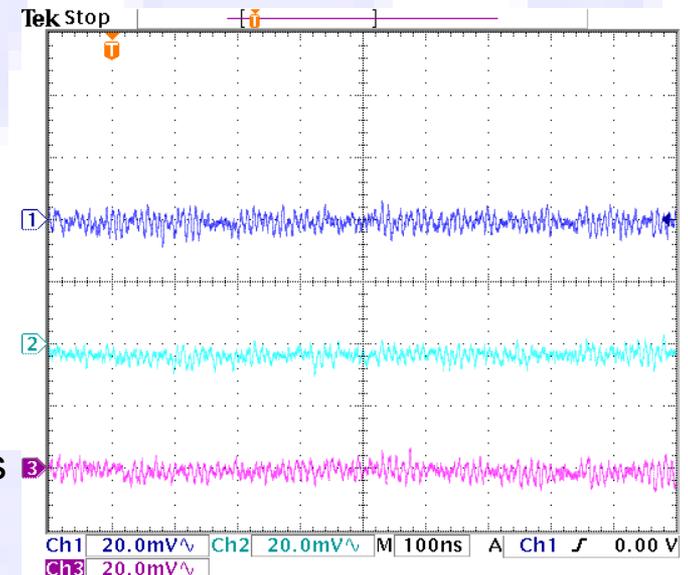


# Extreme Positioning Resolution

1. DM design that uses full scale voltage
  - Actuator fabrication complete
2. Compact, low noise, high resolution electronics



- 14 bit, 200 V
- Factory calibrated with on-board calibration values
- USB interface - (Low speed 150 Hz)
- Scales to > 10k channels
- High speed interface options will be available
  - Digital input supports 35 kHz frame rate
  - Analog Output  $f_{-3db} > 5$  kHz

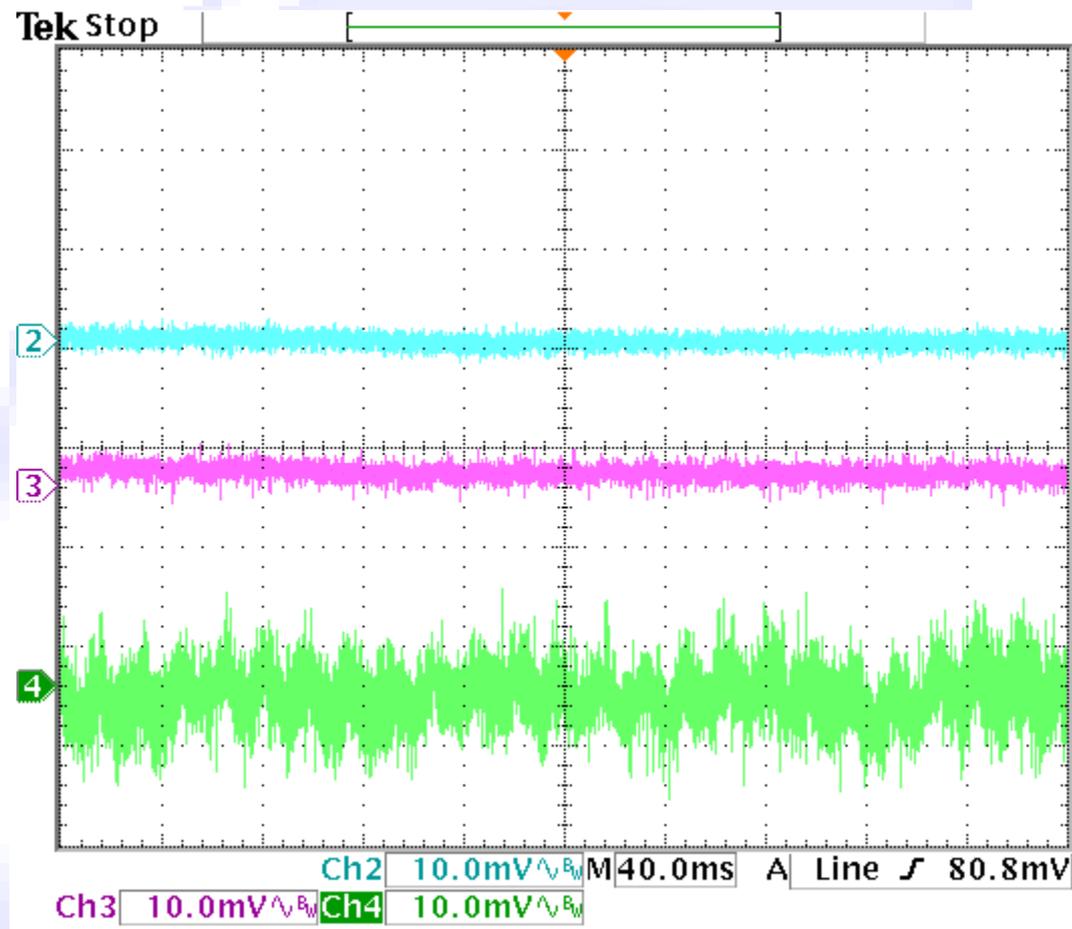


**Unfiltered Noise: 3.3 mV rms**



# Noise Filtering

- Noise is mostly high frequency
- Low-speed applications can take advantage of filtering



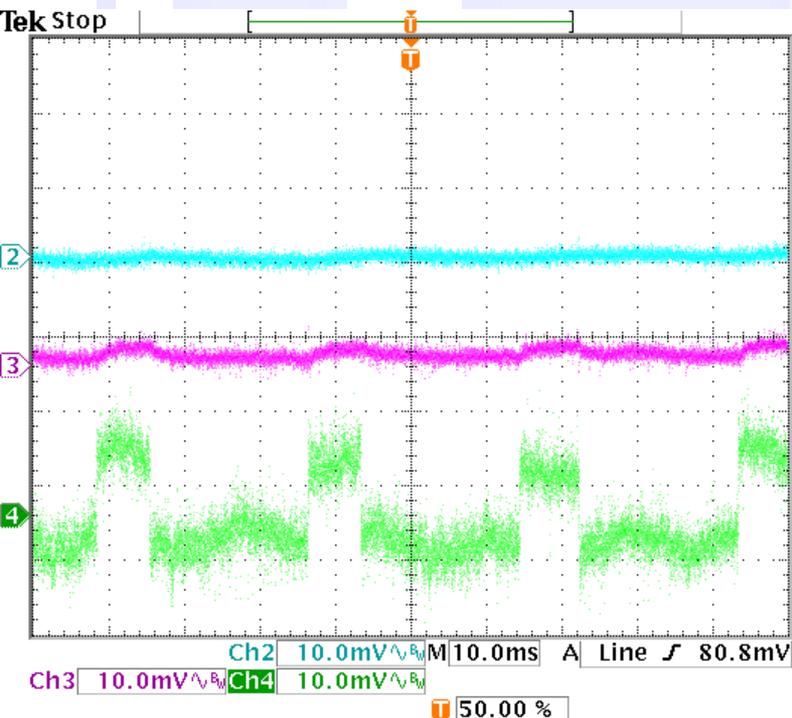
2<sup>nd</sup> Filter Output  
(15.9 Hz F<sub>-3dB</sub>)

1<sup>st</sup> Filter Output  
(15.1 Hz F<sub>-3dB</sub>)

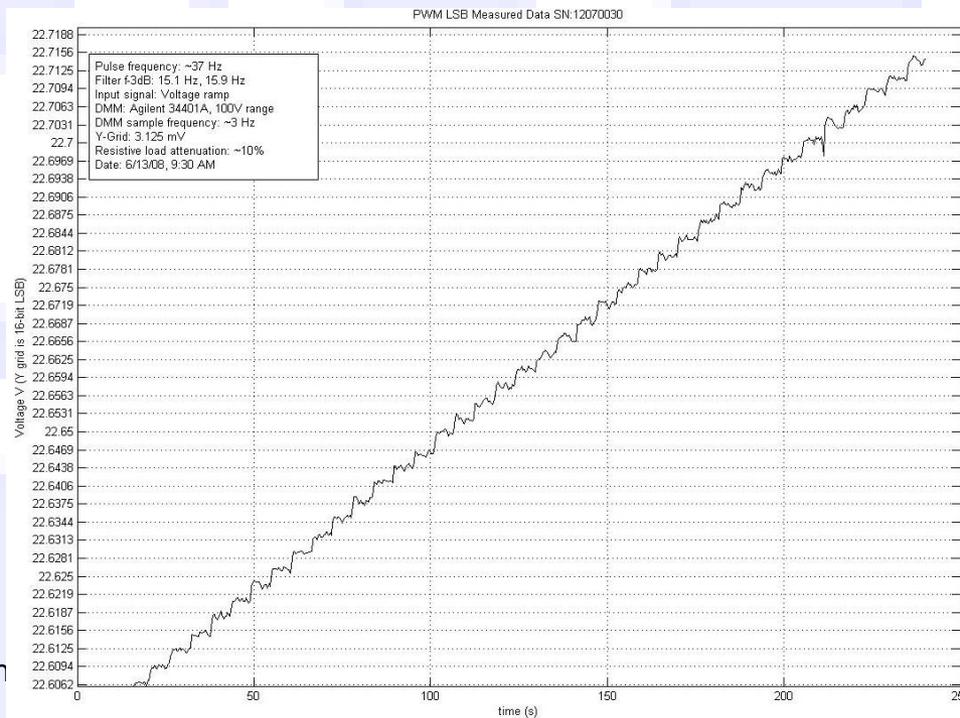
Unfiltered Output

# Modulation + Filtering = Super Resolution

- LSB modulation with low-pass filtering
  - 16+ bits resolution
- First demonstration modulated at ~35 Hz shows 16-bit resolution
- >5 kHz modulation when implemented in firmware

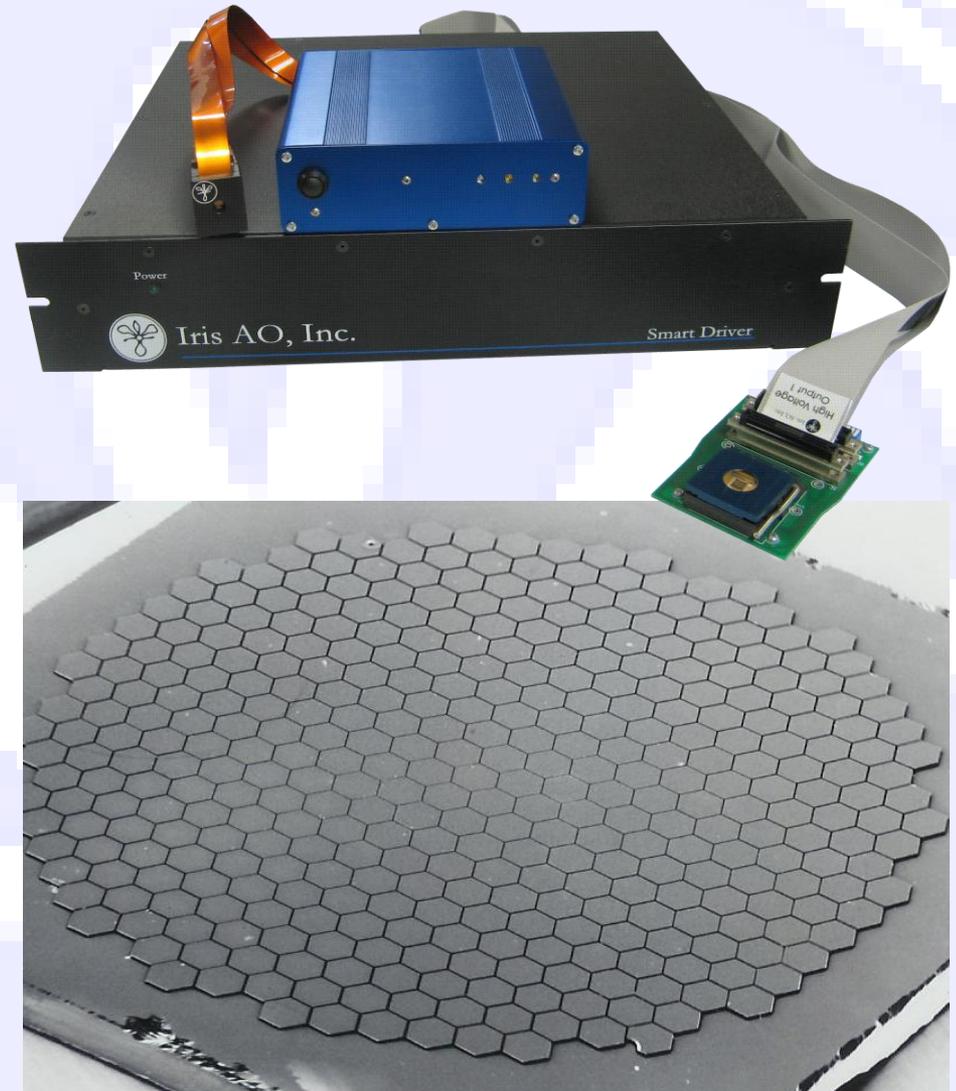


5 Jun 2008 10:56:43

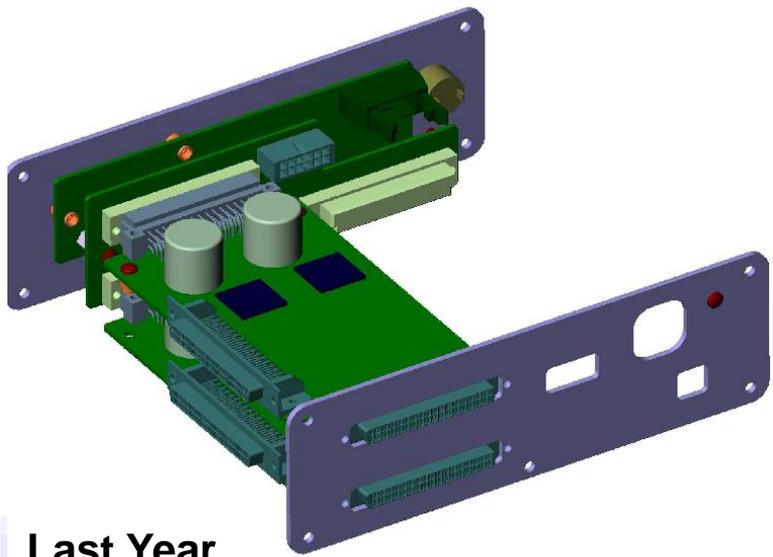


# Scalability

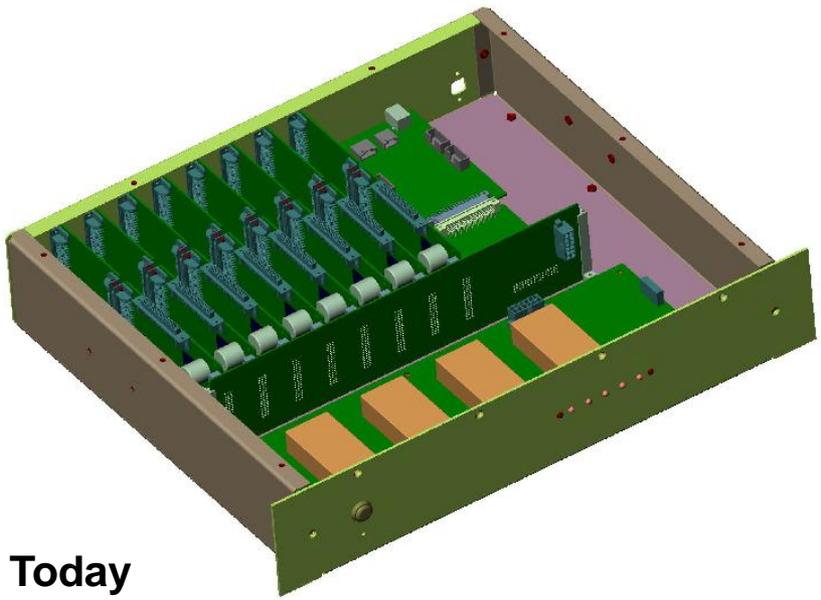
- Scalable drive electronics
  - NASA Phase II SBIR
- 163-segment DM
  - NIH Phase II SBIR
- $10^3$  segment DM
  - Funding TBD
  - Preliminary experiments where possible



# Smart Driver II Electronics – 512 Channels



Last Year



Today



Today

August 26<sup>th</sup>, 2008



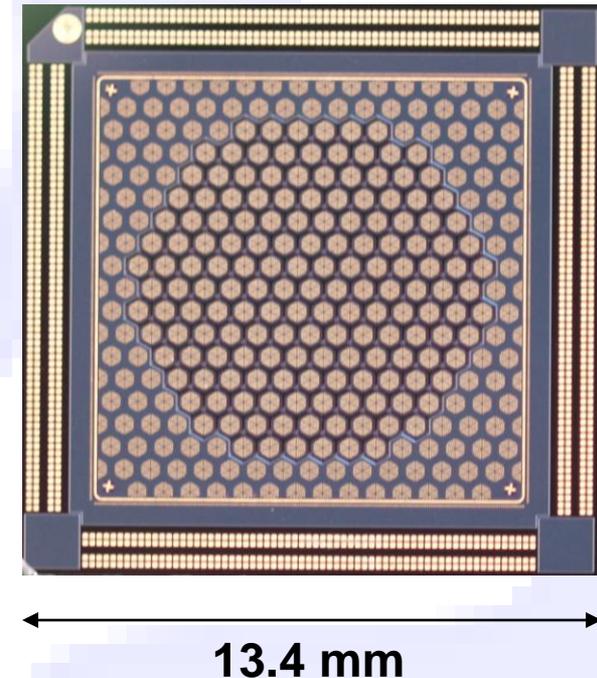
Dec. 2008

Mirror Technology Days



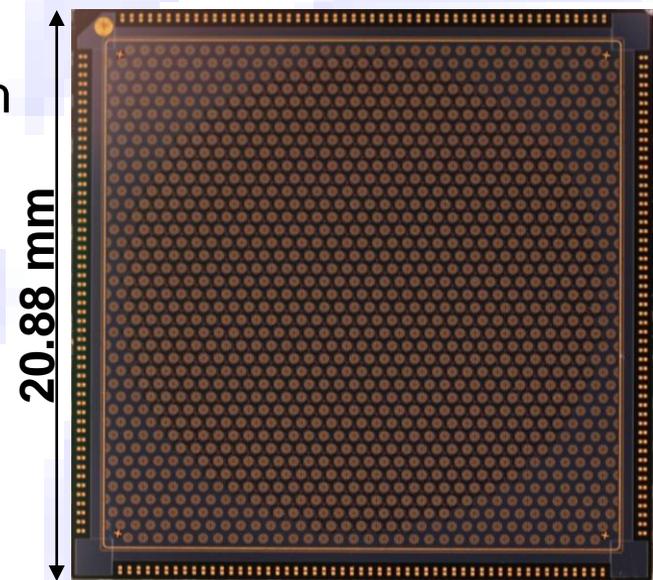
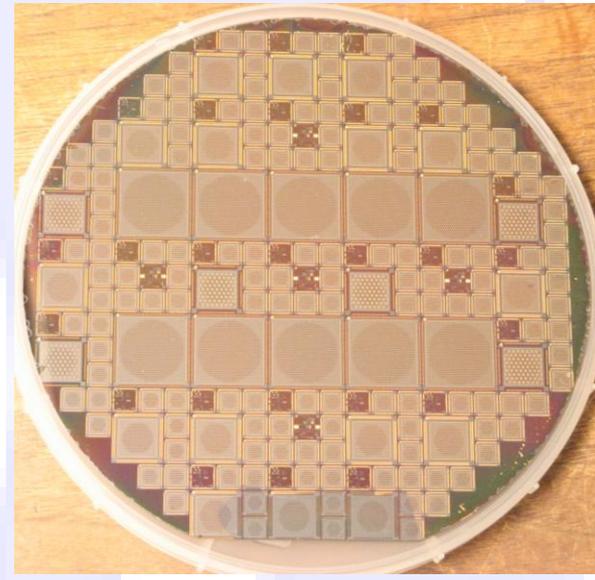
# 163 Segment (S163-X) DM Development

- Funded by NIH Phase II SBIR
  - Sept 2007 – August 2009
- Actuator wafer process development underway
  - 1<sup>st</sup> Run: Electrode and mechanical layer only
  - 2<sup>nd</sup> Run: Includes wiring layer
    - Fabrication begins 9/2/08
- Mirror-wafer fabrication to begin 10/2008
  - Mirror-wafer process already developed



# $10^3$ Segment DM

- Path-finding research into  $10^3$  segment class DMs
- Developing along with S163-X
  - Multi-project wafer
  - 1st and 2nd fabrication runs
- 925 actuators w/ganged electrodes to reduce wiring
- Segment pitch matches EPIC point design
  - Extrasolar Planetary Imaging Coronagraph (EPIC) - Discovery Mission Concept
  - Clampin/Lyon GSFC
- Additional funding TBD
  - Proposing Phase I SBIR to NASA GSFC



# Summary

- On our way to meeting Phase II SBIR goals
  - Low-noise electronics
  - Super-resolution technique
  - DM flatness improving (2X since start of contract)
    - Expect to reach 1-3 nm rms surface figure error goal
- Developing larger mirrors
  - S163-X prototype development
  - $10^3$  segment DM proof-of-concept development
    - Needs additional funding to wire and package

# Acknowledgements

## Funding Sources



- NASA – Phase II SBIR, (Extreme Precision DM Testing and Development)
  - NNG07CA06C



- Center for Adaptive Optics (DM Process Development)
  - National Science Foundation Science and Technology: No. AST – 9876783



- National Eye Institute – Phase II SBIR (DM Process Development)
  - 2 R44 EY015381-02A1



- US Air Force – Phase II SBIR (DM Control)
  - FA8650-04-M-6518



- National Science Foundation – Phase II SBIR (Ancillary Process Development)
  - DMI-0522321

## R&D Fabrication Facility



- Berkeley Microfabrication Laboratory

## Research Collaboration



- Berkeley Sensor & Actuator Center